**Amendments to the Claims:** 

This listing of claims will replace all prior versions, and listings, of claims in the

application:

**Listing of Claims:** 

1. (Currently Amended) A dielectric material for forming a structure of an integrated circuit,

said dielectric material comprising:

a plurality of fluorinated carbon nanostructures; and

a copolymer layer binding said fluorinated carbon nanostructures to define the dielectric

<u>material</u>.

2. (Cancelled)

3. (Previously Presented) The dielectric material of claim 1 wherein said fluorinated carbon

nanostructures comprise a plurality of fluorinated carbon nanotubes.

4. (Original) The dielectric material of claim 1 wherein said dielectric material has a dielectric

constant of less than about 3.

5. (Original) The dielectric material of claim 1 wherein said structure further comprises at least

one conductive feature disposed in said dielectric material.

6. (Previously Presented) The dielectric material of claim 1 wherein said fluorinated carbon

nanostructures comprise a plurality of fluorinated carbon buckyballs.

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7. (Original) The dielectric material of claim 1 further comprising a cap layer on said dielectric

material.

8. (Currently Amended) The dielectric material of claim 7 wherein said fluorinated carbon

nanostructures, said copolymer layer, and said cap layer have an effective dielectric constant of

less than about 3.

9. (Cancelled)

10. (Currently Amended) The dielectric material of claim [[7]] 1 wherein said fluorinated

carbon nanostructures and said copolymer layer have an effective dielectric constant of less than

about 3.

11. (Currently Amended) A semiconductor structure formed on a substrate, comprising:

a dielectric layer comprising a plurality of fluorinated carbon nanostructures and a

copolymer layer binding said fluorinated carbon nanostructures; and

at least one conductive feature in said dielectric layer, said at least one conductive feature

electrically isolated from nearby conductive features by portions of said dielectric layer.

12. (Original) The semiconductor structure of claim 11 wherein said dielectric layer has an

exposed surface, and further comprising:

a cap layer of an insulating material at least partially covering said exposed surface, said

cap layer having a top surface, and said conductive feature having a top surface substantially

coplanar with said top surface of said cap layer.

13. (Cancelled)

14. (Previously Presented) The semiconductor structure of claim 11 wherein said fluorinated

carbon nanostructures comprise a plurality of fluorinated carbon nanotubes.

15. (Original) The semiconductor structure of claim 11 wherein said dielectric layer has a

dielectric constant of less than about 3.

16. (Original) The semiconductor structure of claim 11 wherein said structure comprises a

plurality of conductors electrically isolated by said layer of said dielectric material.

17. (Previously Presented) The semiconductor structure of claim 11 wherein said fluorinated

carbon nanostructures comprise a plurality of fluorinated carbon buckyballs.

18. (Previously Presented) The semiconductor structure of claim 11 further comprising:

a cap layer disposed on said fluorinated carbon nanostructures.

19. (Currently Amended) The semiconductor structure of claim 18 wherein said fluorinated

carbon nanostructures, said copolymer layer, and said cap layer collectively have a dielectric

constant of less than about 3.

20. (Original) The semiconductor structure of claim 11 further comprising:

a substrate selected from the group consisting of an interconnect level, a dielectric

material, a buried barrier layer, a metallization line, and a semiconductor wafer.

21. (Currently Amended) An integrated circuit comprising a plurality of circuit elements and

the semiconductor structure of claim 11, said at least one conductive feature being electrically

coupled with at least one of said circuit elements.

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## 22. (Cancelled)

23. (Currently Amended) The dielectric material of claim [[22]] 11 wherein said fluorinated carbon nanostructures and said copolymer layer have an effective dielectric constant of less than about 3.

24-45. (Cancelled)